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Kind regards,

Team Nexperia

PH3230S

N-channel TrenchMOS intermediate level FET

Rev. 04 — 27 November 2009

Product data sheet

1. Product profile

1.1 General description

Intermediate level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Saves PCB space due to small footprint
- Simple gate drive required due to low gate charge
- Suitable for logic level gate drive sources

1.3 Applications

- Computer motherboards
- DC-to-DC convertors

- Notebook computers
- Switched-mode power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	-	30	V
I_D	drain current	$T_{mb} = 25 ^{\circ}\text{C}; V_{GS} = 10 \text{V};$ see <u>Figure 1</u> and <u>3</u>	-	-	100	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	62.5	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 5 \text{ V}; I_D = 50 \text{ A};$ $V_{DS} = 10 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 12</u>	-	13	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C};$ see <u>Figure 9</u> and <u>10</u>	-	2.7	3.2	mΩ



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2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb	D
3	S	source		
4	G	gate	9	
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PH3230S	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

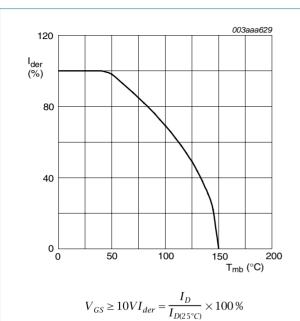
4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

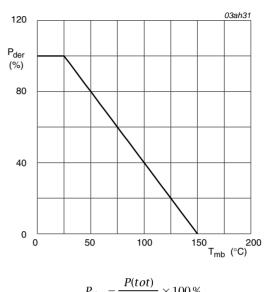
Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 ^{\circ}\text{C}; T_j \le 150 ^{\circ}\text{C}$	-	30	V
V_{GS}	gate-source voltage		-20	20	V
I _D	drain current	$V_{GS} = 10 \text{ V}$; $T_{mb} = 25 \text{ °C}$; see <u>Figure 1</u> and <u>3</u>	-	100	Α
		V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	63	Α
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	300	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	62.5	W
T _{stg}	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dra	ain diode				
Is	source current	$T_{mb} = 25 ^{\circ}C$	-	52	Α
I _{SM}	peak source current	t _p ≤ 10 μs; pulsed; T _{mb} = 25 °C	-	156	Α
Avalanche	ruggedness				
E _{DS(AL)R}	repetitive drain-source avalanche energy	$V_{GS} = 10 \text{ V}; I_D = 5 \text{ A}; V_{sup} = 15 \text{ V}; R_{GS} \ge 50 \Omega$	-	2.5	mJ
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 50 A; V_{sup} ≤ 15 V; unclamped; R_{GS} = 50 Ω	-	250	mJ

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Normalized continuous drain current as a Fig 1. function of mounting base temperature

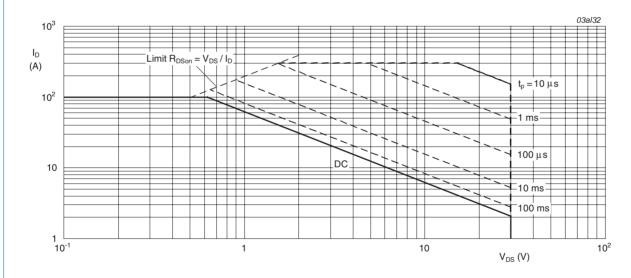
Product data sheet



$$P_{der} = \frac{P(tot)}{P_{tot(25^{\circ}C)}} \times 100\%$$

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Normalized total power dissipation as a Fig 2. function of mounting base temperature



 $T_{mb} = 25$ °C; I_{DM} is single pulse

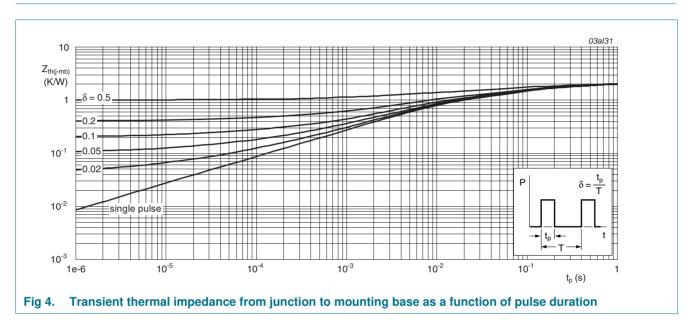
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W



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Characteristics

Table 6. Characteristics

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Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 10 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	30	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see Figure 8	1	2	3	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nA
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nA
R_{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 9	-	5	6.5	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 9 and 10	-	2.7	3.2	mΩ
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 11</u>	-	8.0	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -50 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; T_j = 25 \text{ °C}$	-	46	-	ns
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 50 \text{ A}; V_{DS} = 10 \text{ V}; V_{GS} = 5 \text{ V};$	-	42	-	nC
Q_{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 12</u>	-	21	-	nC
Q_{GD}	gate-drain charge		-	13	-	nC
C _{iss}	input capacitance	$V_{DS} = 10 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	4100	-	pF
C _{oss}	output capacitance	$T_j = 25 ^{\circ}\text{C}$; see Figure 13	-	1150	-	pF
C_{rss}	reverse transfer capacitance		-	750	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 10 V; R_L = 0.4 Ω ; V_{GS} = 10 V;	-	14	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega; T_j = 25 \text{ °C}$	-	37	-	ns
t _{d(off)}	turn-off delay time		-	85	-	ns
t _f	fall time		-	37	-	ns
9 _{fs}	transfer conductance	$V_{DS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see Figure 14	39	75	-	S

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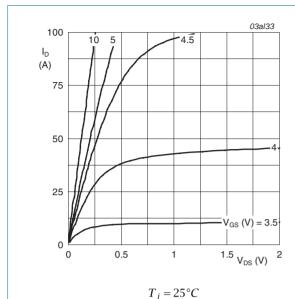
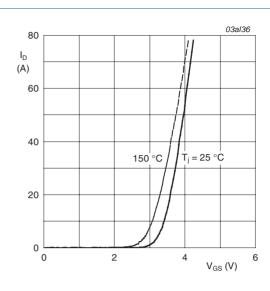


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



 $T_j = 25$ °C and 150°C; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values

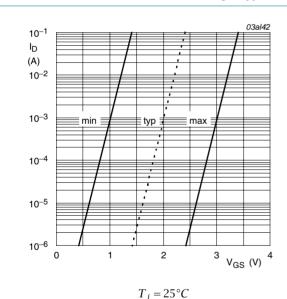
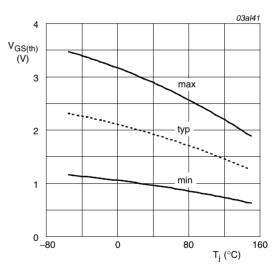


Fig 7. Sub-threshold drain current as a function of gate-source voltage



 $I_D = 1mA; V_{DS} = V_{GS}$

Fig 8. Gate-source threshold voltage as a function of junction temperature

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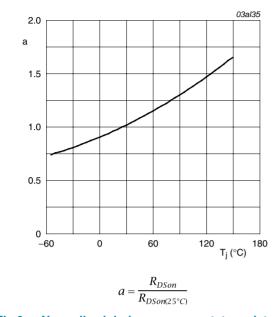


Fig 9. Normalized drain-source on-state resistance factor as a function of junction temperature

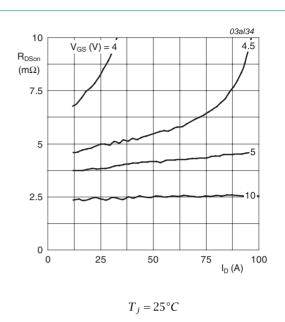


Fig 10. Drain-source on-state resistance as a function of drain current; typical values

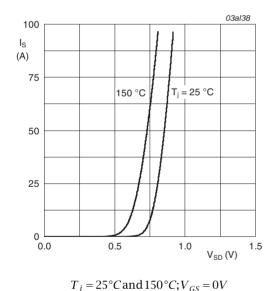
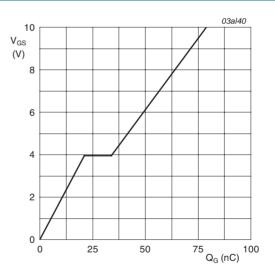


Fig 11. Source current as a function of source-drain voltage; typical values



 $T_j = 25$ °C; $I_D = 50A$; $V_{DD} = 10V$

Fig 12. Gate-source voltage as a function of gate charge; typical values

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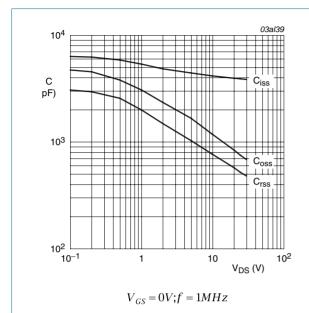
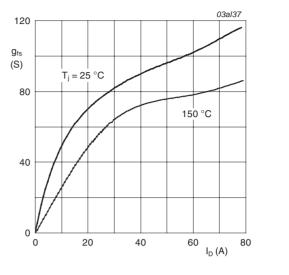


Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



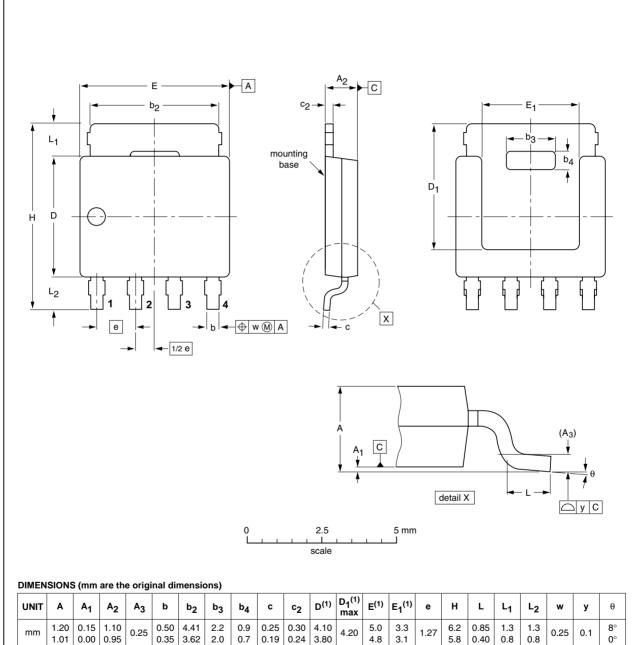
 $T_j = 25$ °C and 150°C; $V_{DS} > I_D \times R_{DSon}$

Fig 14. Forward transconductance as a function of drain current; typical values

Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



UNIT	Α	A ₁	A ₂	А3	b	b ₂	b ₃	b ₄	С	c ₂	D ⁽¹⁾	D ₁ ⁽¹⁾ max	E ⁽¹⁾	E ₁ ⁽¹⁾	е	Н	L	L ₁	L ₂	w	у	θ
mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19	0.30 0.24	4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

	OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
	VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
	SOT669		MO-235			04-10-13 06-03-16
_						

Fig 15. Package outline SOT669 (LFPAK)

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Revision history

Table 7. **Revision history**

Product data sheet

•			
Release date	Data sheet status	Change notice	Supersedes
20091127	Product data sheet	-	PH3230S-03
		en redesigned to compl	ly with the new identity
 Legal texts 	have been adapted to the	e new company name v	vhere appropriate.
20040302	Product data	-	PH3230S-02
20030423	Product data	-	PH3230S-01
20030212	Preliminary data	-	-
	20091127 • The format guidelines • Legal texts 20040302 20030423	 20091127 Product data sheet The format of this data sheet has bee guidelines of NXP Semiconductors. Legal texts have been adapted to the 20040302 Product data 20030423 Product data 	Product data sheet The format of this data sheet has been redesigned to compliquidelines of NXP Semiconductors. Legal texts have been adapted to the new company name version of the semiconduct of the new company name version of the semiconductors. Product data Product data -

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9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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